

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT  
(Use several sheets if necessary)

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APPLICANT MASAYA ASAO, et al.

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GROUP 1751




U.S. PATENT DOCUMENTS

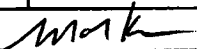
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	B. D. Cullity, "Elements of X-RAY DIFFRACTION", 2 <sup>nd</sup> Ed., Addison-Wesley Publishing Company, Inc., pp. 100-103. NO PUB DATE PROVIDED
	Diffraction: Real Samples, <a href="http://www-lam.stanford.edu/xlab/MatSci162_172/LectureNotes/04_Real%20Samples.pdf">http://www-lam.stanford.edu/xlab/MatSci162_172/LectureNotes/04_Real%20Samples.pdf</a> , pp. 1-55, visited October 22, 2007.
	5-Lecture notes for Clay Mineralogy, <a href="http://www.gly.uga.edu/schroeder/geol6550/CM05.html">http://www.gly.uga.edu/schroeder/geol6550/CM05.html</a> , pp. 1-8, visited October 22, 2007.

EXAMINER  DATE CONSIDERED 11/6/07

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1

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